

C1812C334G3JACTU

Aliases (C1812C334G3JAC7800) SMD Comm U2J, Ceramic, 0.33 uF, 2%, 25 VDC, U2J, SMD, MLCC, Ultra-Stable, Low Loss, Class I, 1812, 2.3 mm



General Information	
Series	SMD Comm U2J
Style	SMD Chip
Description	SMD, MLCC, Ultra-Stable, Low Loss, Class I
Features	Ultra-Stable, Low Loss, Class I
RoHS	Yes
Termination	Tin
Marking	No
AEC-Q200	No
Typical Component Weight	67 mg
Shelf Life	78 Weeks
MSL	1

Dimensions	
Chip Size	1812
L	4.5mm +/-0.3mm
W	3.2mm +/-0.3mm
Т	1.1mm +/-0.10mm
S	2.3mm MIN
В	0.6mm +/-0.35mm

L	4.5mm +/-0.3mm	Measurement Condition	I KHZ I.OVrms
W	3.2mm +/-0.3mm	Tolerance	2%
Т	1.1mm +/-0.10mm	Voltage DC	25 VDC
S	2.3mm MIN	Dielectric Withstanding Voltage	62.5 VDC
В	0.6mm +/-0.35mm	Temperature Range	-55/+125°C
		Temp. Coefficient	U2J
Packaging Specifications		Capacitance Change with	-750+/-120 ppm/C, 1k
Packaging	T&R, 180mm, Plastic Tape	Reference to +25°C and 0 VDC 1.0Vrms Applied (TCC)	1.0Vrms
Packaging Quantity	1000	Discipation Factor	0.1% 1 kHz 1.0\/rms

Specifications	
Capacitance	0.33 uF
Measurement Condition	1 kHz 1.0Vrms
Tolerance	2%
Voltage DC	25 VDC
Dielectric Withstanding Voltage	62.5 VDC
Temperature Range	-55/+125°C
Temp. Coefficient	U2J
Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC)	-750+/-120 ppm/C, 1kHz 1.0Vrms
Dissipation Factor	0.1% 1 kHz 1.0Vrms
Aging Rate	0.1% Loss/Decade Hour: Referee Time is 1000 Hours
Insulation Resistance	3.0303 GOhms

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